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(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Attorney Docket No. 0756-1998

Serial No. 09/352,194

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI et al.

Filing Date: July 13, 1999

Group Art Unit: 2811

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
H.I.	5,594,569	1/14/97	Konuma et al.	349	122	7/20/94
H.I.	5,643,826	7/1/97	Ohtani et al.	437	150	10/25/94
H.I.	5,923,962	7/13/99	Ohtani et al.	438	150	4/28/95

**FOREIGN PATENT DOCUMENTS**

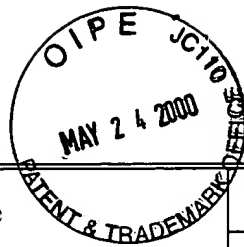
Document Number	Date	Country	Class	Subclass	Translation Yes No
H.I. 7-130652	5/19/95	Japan	—	—	Abstract

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

H.I.	"Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Ryuichi Shimokawa et al., Japanese Journal of Applied Physics, Vol. 27, No. 5, pages 751-758, 1988.
H.I.	"Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLC D Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability", H. Furue et al., SID 1998
H.I.	"A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time", T. Yoshida et al., SID DIGEST, pages 841-844, 1997.
H.I.	"Thresholds antiferroelectricity in liquid crystals and its application to displays", S. Inui et al., J. Mater. Chem., 6 (4), pages 671-673, 1996.

Examiner *Fernando Toledo*Date Considered *9.25.00*

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Sheet 1 of 1Form PTO-1449 U.S. Department of Commerce  
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Examiner Initial	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date (if approp.)
<i>ht</i>	5,854,096	12/29/98	Ohtani et al.	438	166	

**FOREIGN PATENT DOCUMENTS**

Document Number	Date	Country	Class	Subclass	Translation Yes No

**OTHER DOCUMENTS (Including Author, Title, Relevant Pages, Date, Place of Publication)**


Examiner *Fernando Toledo*Date Considered *9.25.00*

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